

<b>Notice of References Cited</b>	Application/Control No. 10/673,138	Applicant(s)/Patent Under Reexamination MITROVIC, ANDREJ S.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,802,045	10-2004	Sonderman et al.	703/22
	B	US-5,719,796	02-1998	Chen, Vincent Ming Chun	703/13
	C	US-6,615,097	09-2003	Ozaki, Hiroji	703/22
	D	US-6,643,616	11-2003	Granik et al.	703/13
	E	US-6,757,645	06-2004	Chang et al.	703/13
	F	US-6,812,045	11-2004	Nikoonahad et al.	438/14
	G	US-6,905,895	06-2005	Coss et al.	438/16
	H	US-5,866,437	02-1999	Chen et al.	438/14
	I	US-2003/0135302	07-2003	Hung et al.	700/245
	J	US-2004/0102934	05-2004	Chang, Fang-Cheng	703/001
	K	US-2005/0016947	01-2005	Fatke et al.	216/002
	L	US-2003/0078738	04-2003	Wouters et al.	702/22
	M	US-2004/0078319	04-2004	Madhavan et al.	705/038

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Emerging Paradigms in Semiconductor Manufacturing"; Paul P. Castrucci; 1990 Int'l Semiconductor Mfg. Science Symposium; IEEE 1990
	V	"Mathematic-Physical Engine: Parallel Processing for Modeling and Simulation of Physical Phenomena"; V.K.Jain et al; IEEE 1994
	W	
	X	

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
<input checked="" type="checkbox"/>	A	US-6,571,371	05-2003	Coss et al.	700/120
<input checked="" type="checkbox"/>	B	US-6,628,809	09-2003	Rowe et al.	382/115
<input checked="" type="checkbox"/>	C	US-6,728,591	04-2004	Hussey et al.	700/121
<input checked="" type="checkbox"/>	D	US-6,763,277	07-2004	Allen et al.	700/100
<input checked="" type="checkbox"/>	E	US-6,774,998	08-2004	Wright et al.	356/401
<input type="checkbox"/>	F	US-			
<input type="checkbox"/>	G	US-			
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<input type="checkbox"/>	K	US-			
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<input type="checkbox"/>	N					
<input type="checkbox"/>	O					
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<input type="checkbox"/>	U	
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